DELKIN DEVICES

Utility

mSATA Solid State Drive Engineering Specification

Document Number: L500644

Revision: C



Product Overview

Capacity

32GB up to 1TB

SATA Interface

- SATA Revision 3.0
- SATA 1.5Gbps, 3Gbps, and 6Gbps interface

Flash Interface

Flash type: MLC

Performance

Read: up to 540 MB/s

Write: up to 510 MB/s

• Power Consumption^{Note1}

Active mode: < 4,200mW

Idle mode: < 1,500mW

• TBW (Terabytes Written) Note2

• 1028 TBW for 512GB

MTBF

More than 2,000,000 hours

Features

- Static and Dynamic Wear Leveling
- Bad Block Management
- TRIM
- NCQ
- SMART
- Over-Provisioning
- Firmware Update Capability

Low Power Management

DIPM/HIPM Mode

Temperature Range

Operation: 0°C ~ 70°C

Storage: -40°C ~ 85°C

RoHS compliant

Notes:

- 1. Please see "4.2 Power Consumption" for details.
- 2. Please see "TBW (Terabytes Written)" in Chapter 2" for details.

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1. INTRODUCTION

1.1. General Description

Delkin Devices' Utility mSATA Solid State Drive (SSD) delivers all the advantages of flash disk technology with Serial ATA III interface and is fully compliant with the JEDEC MO-300B form factor standard. The mSATA draws significantly lower power compared to traditional hard drives and is also much smaller and lighter. The drive is available in capacities from 32GB to 1TB, capable of reaching speeds up to 540MB/s read and 520MB/s write (measured by CrystalDiskMark v3.0).

1.2. Controller Block Diagram

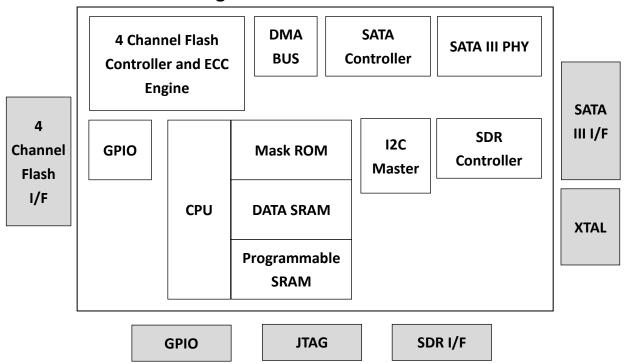


Figure 1-1 mSATA SSD Controller Block Diagram

1.3. Product Block Diagram

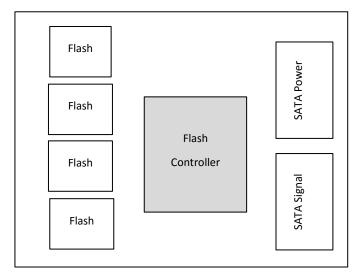


Figure 1-2 mSATA SSD Product Block Diagram

1.4. Flash Management

1.4.1. Error Correction Code (ECC)

Flash memory cells will deteriorate with use, which might generate random bit errors in the stored data. Thus, Delkin's mSATA SSD applies the BCH ECC algorithm, which can detect and correct errors occur during read process, ensure data been read correctly, as well as protect data from corruption.

1.4.2. Wear Leveling

NAND flash devices can only undergo a limited number of program/erase cycles, and in most cases, the flash media are not used evenly. If some areas are updated more frequently than others, the lifetime of the device would be reduced significantly. Thus, Wear Leveling is applied to extend the lifespan of NAND flash by evenly distributing write and erase cycles across the media.

Delkin utilizes advanced Wear Leveling algorithms, which can efficiently distribute flash usage through the whole flash media area. Moreover, by implementing both dynamic and static Wear Leveling algorithms, the life expectancy of the NAND flash is greatly improved.

1.4.3. Bad Block Management

Bad blocks are blocks that include one or more invalid bits, and their reliability is not guaranteed. Blocks that are identified and marked as bad by the manufacturer are referred to as "Initial Bad Blocks". Bad blocks that are developed during usage of the flash are named "Later Bad Blocks".

Delkin implements an efficient bad block management algorithm to detect the factory-produced bad blocks and manages any bad blocks that appear with use. This practice further prevents data being stored into bad blocks and improves data reliability.

1.4.4. TRIM

TRIM is a feature which helps improve the read/write performance and speed of solid-state drives (SSD). Unlike hard disk drives (HDD), SSDs are not able to overwrite existing data, so the available space gradually becomes smaller with each use. With the TRIM command, the operating system can inform the SSD which blocks of data are no longer in use and can be removed permanently. Thus, the SSD will perform an erase action, which prevents unused data from occupying blocks.

1.4.5. SMART

SMART, an acronym for Self-Monitoring, Analysis and Reporting Technology, is an open standard that allows a drive to automatically detect its health and report potential failures. When a failure is recorded by SMART, users can choose to replace the drive to prevent unexpected outage or data loss. Moreover, SMART can inform users of impending failures while there is still time to perform proactive actions, such as copy data to another device.

1.4.6. Over-Provisioning

Over Provisioning refers to the inclusion of extra NAND capacity in a SSD, which is not visible or usable by users. With Over Provisioning, the performance and IOPS (Input/Output Operations per Second) are improved by providing the controller additional space to manage P/E cycles, which enhances the reliability and endurance as well. Moreover, the write amplification of the SSD becomes lower when the controller writes data to the flash.

1.4.7. Firmware Upgrades

Firmware can be considered as a set of instructions on how the device communicates with the host. Firmware can be upgraded when new features are added, compatibility issues are fixed, or read/write performance gets improved, as controlled by the user.

1.5. Low Power Management

1.5.1. DIPM/HIPM Mode

SATA interfaces contain two low power management states for power saving: Partial and Slumber modes. In Partial mode, the device must resume full operation within 10 microseconds, whereas in Slumber mode, the device has 10 milliseconds to become fully operational. SATA interfaces allow low power modes to be initiated by Host (HIPM, Host Initiated Power Management) or Device (DIPM, Device Initiated Power Management). As for HIPM, Partial or Slumber mode can be invoked directly by the software. For DIPM, the device will send requests to enter Partial or Slumber mode.

1.6. Power Loss Protection: Flushing Mechanism

Power Loss Protection is a mechanism to prevent data loss during unexpected power failures. DRAM is volatile memory and frequently used as temporary cache or buffer between the controller and the NAND flash to improve SSD performance. However, one major concern of the DRAM is that data could be lost in the event of a power failure. Accordingly, the Delkin SATA controller applies the *GuaranteedFlush* technology, which requests the controller to transfer data to the cache. Only when the data is fully committed to the NAND flash will the controller send acknowledgement (ACK) to the host. Such implementation can prevent false-positive performance and the risk of power cycling issues.

Additionally, it is critical for a controller to shorten the time the in-flight data stays in the cache. Thus, Delkin's controller applies an algorithm to reduce the amount of data residing in the cache to provide better performance. This *SmartCacheFlush* technology allows incoming data to have only a brief "pit stop" in the cache and then move straight to the NAND flash. If the flash is jammed due to particular file sizes (such as random 4KB data), the cache will be treated as an "organizer", consolidating incoming data into groups before written into the flash to improve write amplification. In summary, with this advanced Flush Mechanism, Delkin's controller provides the reliability and data protection required by today's applications and hosts.

1.7. Advanced Device Security Features

1.7.1. Secure Erase

Secure Erase is a standard ATA command and will write "0xFF" to all cells, to fully wipe all the data on hard drives and SSDs. When this command is issued, the SSD controller will erase its storage blocks and return to its factory default settings.

1.7.2. Write Protect

When a SSD contains too many bad blocks and data is continuously written in, then the SSD may no longer be usable. Thus, Write Protect is a mechanism to prevent data from being written in and protect the accuracy of data that are already stored in the SSD.

1.8. SSD Lifetime Management

1.8.1. Terabytes Written (TBW)

TBW (Terabytes Written) is a measurement of SSDs' expected lifespan, which represents the amount of data written to the device. To calculate the TBW of a SSD, the following equation is applied:

TBW = [(NAND Endurance) x (SSD Capacity) x (WLE)] / WAF

NAND Endurance: NAND endurance refers to the P/E (Program/Erase) cycle rating of NAND flash, per the manufacturer's specification.

SSD Capacity: The SSD capacity is the specific capacity in total of a SSD.

<u>WLE</u>: Wear Leveling Efficiency (WLE) represents the ratio of the average amount of erases on all the blocks to the erases on any block at maximum.

<u>WAF</u>: Write Amplification Factor (WAF) is a numerical value representing the ratio between the amount of data that a SSD controller writes to the flash and the amount of data that the host's flash controller writes. A better WAF, which is near 1, guarantees better endurance and lower frequency of data written to flash memory.

1.8.2. Thermal Monitor (Optional)

Thermal monitors are devices for measuring temperature, and can be found in SSDs in order to issue warnings when SSDs go beyond a certain temperature. The higher temperature the thermal monitor detects, the more power the SSD consumes, causing the SSD to age quickly. Hence, the processing speed of a SSD should be under control to prevent temperature from exceeding a certain range.

1.9. An Adaptive Approach to Performance Tuning

1.9.1. Throughput

Based on the available space of the disk, Delkin SSD controller will regulate the read/write speed and manage the throughput performance. When significant free space remains, the firmware will continuously perform read/write activity. At this stage, there is still no need to implement garbage collection to allocate and release memory, which will accelerate read/write processing to improve the performance. However, when free space is used up, the controller will slow down the read/write processing, and implement garbage collection to release memory blocks. Hence, read/write performance will become slower.

1.9.2. Predict & Fetch

Normally, when the host tries to read data from the SSD, the SSD will only perform one read action after receiving one command. However, Delkin's controller applies *Predict & Fetch* to improve the read speed. When the host issues sequential read commands to the SSD, the SSD will automatically expect that the following will also be read commands. Thus, before receiving the next command, flash has already prepared the data. Accordingly, this accelerates the data processing time, and the host does not need to wait as long to receive data.

2. PRODUCT SPECIFICATIONS

Capacity

From 32GB up to 1TB

Electrical/Physical Interface

- SATA Interface
 - ♦ Compliant with SATA Revision 3.0
 - ♦ Compatible with SATA 1.5Gbps, 3Gbps and 6Gbps interface
 - ♦ NCQ support up to queue depth = 32
 - Supports power management
 - ♦ Supports expanded register for SATA protocol 48 bit addressing mode

ECC Scheme

Capable of correcting up to 72 bits per 1K Byte

• Supports SMART and TRIM commands

Performance and Power Consumption

	Performance		Power Coi	nsumption
Capacity	apacity CrystalDiskMark		Read	Write
	Read (MB/s)	Write (MB/s)	(mW)	(mW)
32GB	375	175	1,640	1,500
64GB	400	170	1,180	1,260
128GB	540	200	2,150	2,380
256GB	540	390	2,190	3,420
512GB	540	520	2,280	4,130
1TB	540	510	2,700	4,160

NOTE:

For more details on Power Consumption, please refer to Chapter 4.2.

• Endurance - TBW (Terabytes Written)

Capacity	TBW
32GB	38
64GB	77
128GB	257
256GB	514
512GB	1028
1TB	2057

NOTES:

1. Many factors affect drive endurance / TBW, including flash configuration, SDR configuration, host platform, usage model, write amplification factor, etc. The figures above are estimates, based on the JEDEC JESD 219A Client workload, and are not guarantees.

Part Numbers

Utility mSATA (0 – 70°C Operating Temperature)

Capacity	Part Number
32GB	MD32APS4R-3N000-2
64GB	MD64APB4R-3N000-2
128GB	MD1HAPC5X-3N000-2
256GB	MD2HAPW5X-3N000-2
512GB	MD5HAPX5X-3N000-2
1TB	MD1TAQL7W-3N000-2

3. ENVIRONMENTAL SPECIFICATIONS

3.1. Environmental Conditions

3.1.1. Temperature and Humidity

• Temperature:

Storage: -40°C to 85°COperational: 0°C to 70°C

- Humidity:
 - ◆ RH 90% under 40°C (operational)

3.1.2. Shock & Vibration

- Shock Specification
 - ◆ 1500G, 0.5ms duration, 3 axes
- Vibration Specification
 - ◆ 20Hz ~80Hz/1.52mm displacement, 80Hz~2000Hz / 20G Acceleration, 3 axes

3.1.3. Electrostatic Discharge (ESD)

- +/- 4KV Contact
- +/- 8KV Contact

3.1.4. EMI Compliance

FCC: CISPR22CE: EN55022BSMI 13438

3.2. MTBF

MTBF, an acronym for Mean Time Between Failures, is a measure of a device's reliability. Its value represents the average time between a repair and the next failure. The measure is typically in units of hours. The higher the MTBF value, the higher the reliability of the device. The predicted result of Delkin's mSATA SSD is more than 2,000,000 hours at 0 °C.

3.3. Certification & Compliance

- RoHS
- SATA III (SATA Rev. 3.0)
- Up to ATA/ATAPI-8 (Including S.M.A.R.T)

4. ELECTRICAL SPECIFICATIONS

4.1. Supply Voltage

Table 4-1 Supply Voltage

Parameter	Rating
Operating Voltage	3.3V

4.2. Power Consumption

Table 4-2 Power Consumption

Table 4-2 I Ower Consumption				
Capacity	Read	Write	Partial	ldle
32GB	1,350	1,300	55	310
64GB	2,010	2,300	300	400
128GB	2,060	2,350	300	405
256GB	2,080	3,560	260	365
512GB	2,380	3,620	270	370
1TB	2,700	4,160	270	1,450

Unit: mW

NOTES:

- 1. The average value of power consumption is achieved based on 100% conversion efficiency.
- 2. The measured power voltage is 3.3V.
- 3. Sequential R/W is measured while testing 4000MB sequential R/W 5 times by CrystalDiskMark.
- 4. Power Consumption may differ according to flash configuration, SDR configuration, and host platform.

5. INTERFACE

5.1. Pin Assignment and Descriptions

Table 5-1 Pin Assignment and Description for mSATA

Table 5-1 Pin Assignment and Description for mSATA				
Pin Number	mSATA Pin	Description		
1	NC	No Connect		
2	+3.3V	3.3V Source		
3	NC	No Connect		
4	DGND	Digital GND		
5	NC	No Connect		
6	NC	No Connect		
7	NC	No Connect		
8	NC	No Connect		
9	DGND	Digital GND		
10	NC	No Connect		
11	NC	No Connect		
12	NC	No Connect		
13	NC	No Connect		
14	NC	No Connect		
15	DGND	Digital GND		
16	NC	No Connect		
17	NC	No Connect		
18	DGND	Digital GND		
19	NC	No Connect		
20	NC	No Connect		
21	SATA GND	SATA Ground Return Pin		
22	NC	No Connect		
23	TXP (out)	Host Receiver Differential Signal Pair		
24	+3.3V	3.3V Source		
25	TXN (out)	Host Receiver Differential Signal Pair		
26	SATA GND	SATA Ground Return Pin		
27	SATA GND	SATA Ground Return Pin		
28	NC	No Connect		
29	SATA GND	SATA Ground Return Pin		
30	NC	No Connect		
31	RXN (in)	Host Transmitter Differential Signal Pair		
32	NC	No Connect		
		•		

33	RXN (in)	Host Transmitter Differential Signal Pair
34	DGND	Digital GND
35	SATA GND	SATA Ground Return Pin
36	NC	No Connect
37	SATA GND	SATA Ground Return Pin
38	NC	No Connect
39	+3.3V	3.3V Source
40	DGND	Digital GND
41	+3.3V	3.3V Source
42	NC	No Connect
43	NC	No Connect
44	DEVSLP	Enter/Exit DevSleep
45	NC	Reserved Pin
46	NC	No Connect
47	NC	Reserved Pin
48	NC	No Connect
49	DAS	Device Activity Signal
50	DGND	Digital GND
51	GND	Default Connect to GND
52	+3.3V	3.3V Source

6. SUPPORTED COMMANDS

6.1. ATA Command List

Table 6-1 ATA Command List

Op Code	Code Description		Description
00h	NOP	97h	IDLE
06h Data Set Management		98h	CHECK POWER MODE
10h-1Fh	Recalibrate	99h	SLEEP
20h	Read Sectors	B0h	SMART
21h	Read Sectors without Retry	B1h	DEVICE CONFIGURATION
24h	Read Sectors EXT	C4h	Read Multiple
25h	Read DMA EXT	C5h	Write Multiple
27h	Read Native Max Address EXT	C6h	Set Multiple Mode
29h	Read Multiple EXT	C8h	Read DMA
2Fh	Read Log EXT	C9h	Read DMA without Retry
30h	Write Sectors	CAh	Write DMA
31h	Write Sectors without Retry	CBh	Write DMA without Retry
34h	Write Sectors EXT	CEh	Write Multiple FUA EXT
35h	Write DMA EXT	E0h	Standby Immediate
37h	Set Native Max Address EXT	E1h	Idle Immediate
38h CFA WRITE SECTORS WITHOUT ERASE		E2h	Standby
39h	Write Multiple EXT	E3h	Idle
3Dh	Write DMA FUA EXT	E4h	Read Buffer
3Fh	Write Long EXT	E5h	Check Power Mode
40h Read Verify Sectors		E6h	Sleep
41h	Read Verify Sectors without Retry	E7h	Flush Cache
42h	Read Verify Sectors EXT	E8h	Write Buffer
45h	WRITE UNCORRECTABLE EXT	EAh	Flush Cache EXT
60h	Read FPDMA Queued	ECh	Identify Device
61h	Write FPDMA Queued	EFh	Set Features
70h-7Fh	Seek	F1h	Security Set Password
90h	Execute Device Diagnostic	F2h	Security Unlock
91h	Initialize Device Parameters	F3h	Security Erase Prepare
92h	Download Microcode	F4h	Security Erase Unit
93h	DOWNLOAD MICROCODE DMA	F5h	Security Freeze Lock
94h	STANDBY IMMEDIATE	F6h	Security Disable Password
95h	IDLE IMMEDIATE	F8h	Read Native Max Address
96h	STANDBY	F9h	Set Max Address

6.2. Identify Device Data

The following table details the sector data returned by the IDENTIFY DEVICE command.

Table 6-2 List of Device Identification

	F: Fixed	-		
Word V: Variable Default Value X: Both		Default Value	Description	
0	F. Botti	0040h	General configuration bit-significant information	
1	X	*1	Obsolete – Number of logical cylinders	
2	V	 C837h	Specific configuration	
3	X	0010h	Obsolete – Number of logical heads (16)	
4-5	Х	00000000h	Retired	
6	Х	003Fh	Obsolete – Number of logical sectors per logical track (63)	
7-8	V	00000000h	Reserved for assignment by the Compact Flash Association	
9	Х	0000h	Retired	
10-19	F	Varies	Serial number (20 ASCII characters)	
20-21	Х	0000h	Retired	
22	Х	0000h	Obsolete	
23-26	F	Varies	Firmware revision (8 ASCII characters)	
27-46	F	Varies	Model number	
47	F	8010h	7:0- Maximum number of sectors transferred per interrupt on	
			MULTIPLE commands	
48	F	4000h	Trusted Computing feature set options(not support)	
49	F	2F00h	Capabilities	
50	F	4000h	Capabilities	
51-52	Х	000000000h	Obsolete	
53	F	0007h	Words 88 and 70:64 valid	
54	Х	*1	Obsolete – Number of logical cylinders	
55	Х	0010h	Obsolete – Number of logical heads (16)	
56	X	003Fh	Obsolete – Number of logical sectors per track (63)	
57-58	Х	*2	Obsolete – Current capacity in sectors	
59	F	0110h	Number of sectors transferred per interrupt on MULTIPLE	
			commands	
60-61	F	*3	Maximum number of sector (28bit LBA mode)	
62	Х	0000h	Obsolete	
63	F	0407h	Multi-word DMA modes supported/selected	
64	F	0003h	PIO modes supported	
65	F	0078h	Minimum Multiword DMA transfer cycle time per word	

Word	F: Fixed V: Variable X: Both	Default Value	Description
66	F	0078h	Manufacturer's recommended Multiword DMA transfer cycle
			time
67	F	0078h	Minimum PIO transfer cycle time without flow control
68	F	0078h	Minimum PIO transfer cycle time with IORDY flow control
69	F	0100h	Additional Supported (support download microcode DMA)
70	F	0000h	Reserved
71-74	F	000000000000000000h	Reserved for the IDENTIFY PACKET DEVICE command
75	F	001Fh	Queue depth
76	F	670eh	Serial SATA capabilities
77	F	0084h	Serial ATA Additional Capabilities
78	F	014Ch	Serial ATA features supported
79	V	0040h	Serial ATA features enabled
80	F	07F8h	Major Version Number
81	F	0000h	Minor Version Number
82	F	346bh	Command set supported
83	F	7d09h	Command set supported
84	F	6063h	Command set/feature supported extension
85	V	3469h	Command set/feature enabled
86	V	bc01h	Command set/feature enabled
87	V	6063h	Command set/feature default
88	V	003Fh	Ultra DMA Modes
89	F	0001h	Time required for security erase unit completion
90	F	001Eh	Time required for Enhanced security erase completion
91	V	0000h	Current advanced power management value
92	V	FFFEh	Master Password Revision Code
93	F	0000h	Hardware reset result. The contents of the bits (12:0) of this
			word can be changed only during the execution of hardware
0.4	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	00001	reset.
94	V	0000h	Vendor's recommended and actual acoustic management value
95	F	0000h	Stream Minimum Request Size
96	V	0000h	Streaming Transfer Time – DMA
97	V	0000h	Streaming Access Latency – DMA and PIO
98-99	F	0000h	Streaming Performance Granularity
100-103	V	*4	Maximum user LBA for 48 bit Address feature set
104	V	0000h	Streaming Transfer Time – PIO

Word	F: Fixed V: Variable X: Both	Default Value	Description	
105	F	0008h	Maximum number of 512-byte blocks per DATA SET	
			MANAGEMENT command	
106	F	4000h	Physical sector size/Logical sector size	
107	F	0000h	Inter-seek delay for ISO-7779 acoustic testing in microseconds	
108-111	F	0000000000000000h	Unique ID	
112-115	F	0000000000000000h	Reserved	
116	V	0000h	Reserved	
117-118	F	0000000h	Words per logical Sector	
119	F	4014h	Supported settings	
120	F	4014h	Command set/Feature Enabled/Supported	
121-126	F	0h	Reserved	
127	F	0h	Removable Media Status Notification feature set support	
128	V	0021h	Security status	
129-140	Х	0h	Vendor specific	
141	Х	0001h	Vendor specific	
142-159	Х	0h	Vendor specific	
160	F	0h	Compact Flash Association (CFA) power mode 1	
161-167	Х	0h	Reserved for assignment by the CFA	
168	F	3h 2.5"	Device Nominal Form Factor	
		4h 1.8"		
		5h Less than 1.8"		
169	F	0001h	DATA SET MANAGEMENT command is supported	
170-173	F	0h	Additional Product Identifier	
174-175		0h	Reserve	
176-205	V	0h	Current media serial number	
206	F	0h	SCT Command Transport	
207-208	F	0h	Reserved	
209	F	4000h	Alignment of logical blocks within a physical block	
210-211	V	0000h	Write-Read-Verify Sector Count Mode 3 (not supported)	
212-213	F	0000h	Write-Read-Verify Sector Count Mode 2 (not supported)	
214-216		0000h	NV Cache relate (not supported)	
217	F	0001h	Non-rotating media device	
218	F	0h	Reserved	
219	F	0h	NV Cache relate (not supported)	
220	V	0h	Write read verify feature set current mode	

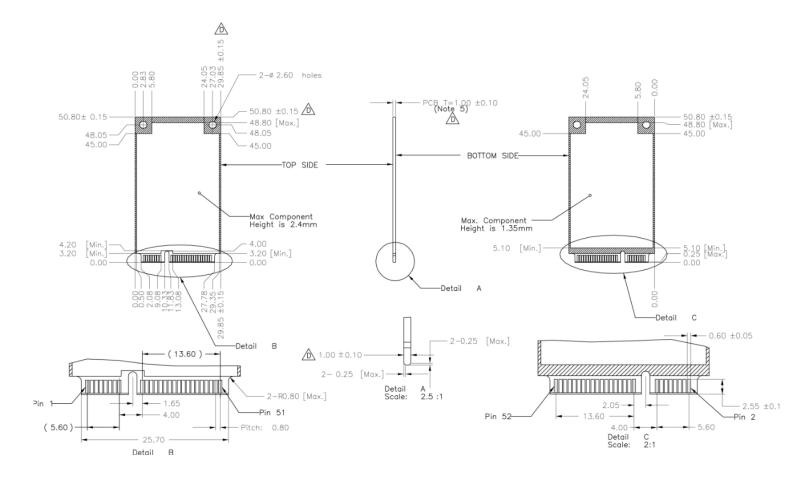
Word	F: Fixed V: Variable X: Both	Default Value	Description		
221		0h	Reserved		
222	F	107Fh	Transport major version number		
223	F	0h	Transport minor version number		
224-229		0h	reserved		
230-233		0h	Extend number of user addressable sectors		
234		0001h	Minimum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h		
235		0080h	Maximum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h		
236-254	F	0h	Reserved		
255	Х	XXA5h XX is variable	Integrity word (Checksum and Signature)		

Table 6-3 List of Device Identification for Each Capacity

Capacity	*1	*2	*3	*4
(GB)	(Word 1/Word 54)	(Word 57 - 58)	(Word 60 - 61)	(Word 100 - 103)
32	3FFFh	FBFC10h	3BA2EB0h	3BA2EB0h
64	3FFFh	FBFC10h	7740AB0h	7740AB0h
128	3FFFh	FBFC10h	EE7C2B0h	EE7C2B0h
256	3FFFh	FBFC10h	FFFFFFh	1DCF32B0h
512	3FFFh	FBFC10h	FFFFFFh	37E436B0h

7. PHYSICAL DIMENSIONS

Dimension: 50.8 ±0.15mm (L) x 29.85 ±0.15mm (W) x 4.85mm (H, max)



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